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Resistivity, thermopower, and thermal conductivity of nickel doped compounds $Cr_{1-x}Ni_xSb_2$ at low temperatures

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1. Introduction

Thermoelectric (TE) materials have recently attracted more and more attentions in the past decade due to their potential applications to refrigerators and electric-power generators [\[1\].](#page-4-0) The conversion efficiency of TE materials is represented by the dimensionless figure of merit, $ZT = S^2T/\rho\kappa$, where S, ρ , κ and T are the thermopower, the electrical resistivity, the thermal conductivity and the absolute temperature, respectively. Thus, high S, low κ , and small ρ are necessary for a good TE material. Although, several classes of materials that are currently under investigation include Bi–Sb–Te-based materials [\[2–6\], P](#page-4-0)bTe-based materials [\[7–9\],](#page-4-0) Zn_4Sb_3 -based materials [\[10–13\],](#page-4-0) Heusler alloys [\[14–16\],](#page-4-0) skutterudites [\[17–19\], m](#page-4-0)etal oxides [\[20–23\], c](#page-4-0)lathrate compounds [\[24,25\], a](#page-4-0)nd pentatellurides [\[26\], t](#page-4-0)heir thermoelectric performance does not meet the requirements of large-scale industrial applications.

Recently, thermoelectric properties of $CrSb₂$ are investigated because of its high thermopower (\sim |-431| μ VK⁻¹ at \sim 60K) [\[27–29\].](#page-4-0) CrSb₂ has an orthorhombic marcasite structure (space group Pnnm) [\[30\]. I](#page-4-0)n this structure, each Cr atom has a distorted octahedral coordination of six nearest-neighbor Sb atoms; each

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ABSTRACT

Substitutional compounds $Cr_{1-x}Ni_xSb_2$ (0 ≤ x ≤ 0.1) were synthesized, and the effect of Ni substitution on transport and thermoelectric properties of $Cr_{1-x}Ni_xSh₂$ were investigated at the temperatures from 7 to 310 K. The results indicated that the magnitudes of the resistivity and thermopower of Cr_{1−x}Ni_xSb₂ decreased greatly with increasing Ni content at low temperatures, owing to an increase in electron concentration caused by Ni substitution for Cr. Experiments also showed that the low-temperature lattice thermal conductivity of $Cr_{1-x}Ni_xSb_2$ decreased substantially with increasing Ni content due to an enhancement of phonon scattering by the increased number of Ni atoms. As a result, the figure of merit, ZT, of lightly doped Cr_{0.99}Ni_{0.01}Sb₂ was improved at T > ~230 K. Specifically, the ZT of Cr_{0.99}Ni_{0.01}Sb₂ at 310 K was approximately ∼29% larger than that of CrSb₂, indicating that thermoelectric properties of $CrSb₂$ can be improved by an appropriate substitution of Ni for Cr.

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Sb atom is tetrahedrally coordinated by three Cr atoms and one Sb atom, which needs 14 electrons to form the covalent bond. As a result, the left two unpaired electrons of each Cr atom do not participate in the covalent bonding, leading to a localized highspin configuration with a d-state manifold per Cr atom $3d^2$ in $CrSb₆ - octahedron$ [\[31–33\].](#page-4-0) As an anti-ferromagnetic intermetallic compound, CrSb₂ has a Neel temperature of $T_N = 273 \pm 2 K [34]$, which decreases monotonically with partial substitution of Cr by Fe [\[35\].](#page-4-0) A plateau of electrical resistivity locates in the temperature range from 50 to 80K in the curve of $\ln \rho$ versus 1000/T and a sharp peak appears at approximately ∼55 K in the curve of magnetic susceptibility χ versus temperature for CrSb₂, implying that an electronic change may occur in the electron-spin system [\[36,37\].](#page-4-0) The partial substitution of Cr by Ru leads to an increase in the thermopower |S| and resistivity ρ of Cr_{1–x}Ru_xSb₂ at room temperature [\[38\]. M](#page-4-0)oreover, CrSb₂ is a narrow-gap semiconductor with an energy gap of 0.07 eV [\[31,38\],](#page-4-0) suggesting that $CrSb₂$ would be a potential thermoelectric material. Recently, we have studied the transport and thermoelectric properties of CrSb₂ after the substitution of Te, Sn, Mn, Ti for Cr, respectively [\[29,39–41\]; a](#page-4-0)nd the ZT of CrSb_{2−x}Te_x, Cr_{1−x}Mn_xSb₂, and Cr_{1−x}Ti_xSb₂ were improved by an appropriate doping, however, the thermoelectric properties of $CrSb_{2−x}Sn_x$ were not optimized due to the decrease in the thermoelectric power factor ($PF = S^2T/\rho$). Additionally, the Neel temperature of CrSb₂ shifts to higher temperatures after Mn substitution, owing to the high spin $3d³$ configuration of Mn [\[40\]. I](#page-4-0)n contrast, the change of Neel temperature could be negligible after Ti substitution due to neutral particles of Ti [\[41\]. I](#page-4-0)t is well known

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Fig. 1. XRD patterns (Cu K α irradiation) for Cr_{1−x}Ni_xSb₂ (x=0, 0.01, 0.05, and 0.10) at room-temperature.

that $NiSb₂$ and $CrSb₂$ have the same crystalline structure [\[30,42\],](#page-4-0) furthermore, it is the low spin $3d^6$ configuration of Ni in NiSb₂ [\[32\]. T](#page-4-0)hus, in the present work Ni doped compounds $Cr_{1-x}Ni_xSb_2$ were prepared, and their electrical resistivity (ρ), themopower (S) and thermal conductivity (k) were investigated in the temperature range from 7 to 310 K.

2. Experimental methods

Polycrystalline samples of $Cr_{1-x}Ni_xSb_2$ (x=0, 0.01, 0.05 and 0.10) were synthesized by the method of melting and alloying. Firstly, the mixtures of constituent elements Cr (purity: 99.9 at.%), Sb (purity: 99.9 at.%) and Ni (purity: 99.9 at.%) in stoichiometric proportions were sealed in evacuated quartz tubes under a pressure of approximately ~2 × 10⁻² Pa. Then they were heated slowly to 650 °C and isothermally kept for 1 week to form Cr_{1−x}Ni_xSb₂ compounds. The phase structure of the obtained samples was examined using X-ray diffraction (XRD, Philips-X' Pert Pro) with Cu K α irradiation. Accurate lattice parameters were determined from d-values of XRD peaks using the standard least-squares refinement method with an Si standard for calibration. To measure their transport properties, the synthesized Cr_{1−x}Ni_xSb₂ powders were compacted by hot pressing (under the pressure of 300 MPa) in vacuum at 400 ◦C for 60 min to form bulk samples. Bar-shaped specimens of with dimensions of ~13 mm × ~3 mm × ~1.5 mm were cut from the bulk samples. All transport properties (i.e. resistivity, thermopower, and thermal conductivity) were measured simultaneously using a physical property measurement system (PPMS, Quantum Design, USA) in the temperature range from 7 to 310 K.

Fig. 3. Plot of the electrical resistivity $\ln \rho$ versus temperature T for Cr_{1−x}Ni_xSb₂ (x=0, 0.01, 0.05, and 0.10). The inset shows variation of the electrical resistivity ρ with temperature T for $Cr_{1-x}Ni_xSb_2$ above 120 K.

The carrier concentration was determined by measurements of the Hall coefficient at room temperature in a field, $H = 0.73T$.

3. Results and discussion

3.1. Phase determination and measurements of lattice parameters after Ni substitution

The XRD patterns of the $Cr_{1-x}Ni_xSb_2$ samples are shown in Fig. 1. It can be seen from curve (a) that all the main diffraction peaks correspond to those of standard JCPDS card of $CrSb₂$ with orthorhombic marcasite structure (space group Pnnm). As compared with that of pristine $CrSb₂$, no obvious changes are observed in the XRD patterns of the doped samples. The values of lattice parameters of $Cr_{1-x}Ni_xSb_2$ are calculated using the XRD data. As plotted in Fig. 2, the lattice parameters a , b and the volume of unit cell V of $Cr_{1-x}Ni_xSb_2$ decrease with increasing Ni content, whereas c increases, which are in agreement with the previous results [\[43,44\].](#page-4-0) In addition, the solid solubility limit of Ni in $CrSb₂$ is quite high due to the similar crystal structure of $CrSb₂$ to that of NiSb₂. These results indicate that Ni has suc-

Fig. 2. Composition (x) dependence of lattice parameters a, b, c and volume of unit cell V for $Cr_{1-x}Ni_xSb_2$ (x = 0, 0.01, 0.05, and 0.10) at room-temperature.

Fig. 4. Plot of Neel temperatures T_N versus doping content x for Cr_{1−x}Mn_xSb₂, $Cr_{1-x}Ni_xSb_2$, $Cr_{1-x}Fe_xSb_2$ and $Cr_{1-x}Ti_xSb_2$.

cessfully substituted for Cr, leading to formation of $Cr_{1-x}Ni_xSb_2$ compounds.

3.2. Electrical resistivity and thermopower

[Fig. 3](#page-1-0) shows the temperature dependence of the electrical resistivity (plotted as $\ln \rho$ versus T) for Cr_{1−x}Ni_xSb₂ at temperatures ranging from 7 to 310 K. All of the samples exhibit semiconductorlike behavior, and the resistivity ρ decreases substantially with increasing Ni content below ∼100 K, however, the resistivity of $Cr_{0.99}Ni_{0.01} Sb₂$ and $Cr_{0.95}Ni_{0.05} Sb₂$ is larger than that of $CrSb₂$ above ∼150 K. In addition, a plateau and a marked anomaly are observed in the $\ln \rho$ –T curve of CrSb₂ [\(Fig. 3\),](#page-1-0) which is well consistent with previous results [\[34,38\]. B](#page-4-0)y comparing curve (a) with curves (b)–(d) in [Fig. 3,](#page-1-0) one can see that the plateau is effectively prohibited by Ni substitution, and the Neel temperature T_N decreases from 273(\pm 2) K for x = 0 to 264(\pm 2) K for x = 0.01, 238(\pm 2) K for x = 0.05, and 195(\pm 2) K for x = 0.10 (Fig. 4(b)) due to the substitution of low spin Ni (3d⁶) for high spin Cr (3d²), leading to a reduction in the effective moment of Cr in $CrSb₂$, which is similar to Fe doped compounds [\[32,35\], b](#page-4-0)ut different from Mn-doped compounds [\[40\], t](#page-4-0)he substitution of high spin Mn $(3d³)$ for Cr with one more unpaired electron leads to the increase in Neel temperature.

In order to examine the temperature behavior of the resistivity for Cr_{1−x}Ni_xSb₂, logarithm of resistivity ln ρ is plotted as a function of T^{-1} in Fig. 5. Their resistivity can be expressed using a thermally activated form in the corresponding temperature regions, written as:

$$
\rho = \rho_0 \exp\left(\frac{\Delta E}{k_B T}\right) \tag{1}
$$

where ρ_0 is the pre-exponential factor, ΔE is the activation energy for conduction, and k_B is the Boltzmann constant. The best fit of the experimental data to Eq. (1) yields four activation energies ΔE_i (i=1–4) for CrSb₂: 32.6 (∼276 K < T < ∼310 K), 35.7 (\sim 60 K < T < \sim 276 K), 4.6 (\sim 12 K < T < \sim 60 K), and 0.9 meV (∼7K < T < ∼12 K), respectively. The value of ΔE_2 is about half of the energy gap (E_g), or 0.07 eV, which is larger than ΔE_1 for CrSb₂, possibly caused by the transition from anti-ferromagnetism to paramagnetism. However, ΔE_3 and ΔE_4 are much smaller than ΔE_2 (or the E_g), indicating that they could be attributed to impurity or defect levels. The decrease of activation energies ΔE_i [\(Fig. 6\)](#page-3-0)

Fig. 5. Plot of $\ln \rho$ versus T⁻¹ for Cr_{1-x}Ni_xSb₂ (x=0, 0.01, 0.05, and 0.10).

Fig. 6. Variation of the activation energies ΔE_i (*i* = 1–4) with the Ni content *x* for $Cr_{1-x}Ni_xSb_2$.

Table 1

Hall coefficent $R_{\rm H}$, carrier contention n_c , and resistivity ρ of Cr_{1−x}Ni_xSb₂ (0 \le x \le 0.10) at room temperature.

Composition (x)		0.01	0.05	0.10
$R_{\rm H}$ (cm ³ C ⁻¹)	-0.48	-0.59	-0.56	-0.25
n_c (\times 10 ²¹ cm ⁻³)	1.31	1.06	1.11	2.54
ρ (\times 10 ⁻⁵ Ω m)	2.31	3.16	2.74	1.13

suggests that a shift in impurity or defect levels toward the edge of conduction band(s), or even a narrowing of the energy gap would occur due to lattice distortion after doping [\(Fig. 2\),](#page-1-0) which is well consistent with previous results [\[39,41\]. O](#page-4-0)n the other hand, the donor level could be introduced into the energy gap of CrSb₂ after Ni substitution. As a result, both of the factors could lead to an increase in electron concentration, in agreement with the decrease in resistivity after Ni doping at $T \sim 100$ K. Furthermore, the electron concentration calculated from measurements of the R_H at room temperature is 1.31×10^{21} cm⁻³ for x=0, 1.06×10^{21} cm⁻³ for x=0.01, 1.11×10^{21} cm⁻³ for x=0.05, and 2.54×10^{21} cm⁻³ for $x = 0.10$ (Table 1), which could explain the observed variation in the resistivity of Cr_{1−x}Ni_xSb₂ above ~150 K [\(Fig. 3\).](#page-1-0)

Fig. 7 gives thermopower as a function of temperature for $Cr_{1-x}Ni_xSb_2$. The thermopower for all the samples is negative,

Fig. 7. Variation of thermopower S with temperature T for $Cr_{1-x}Ni_xSb_2$ (x=0, 0.01, 0.05, and 0.10). The inset shows the variation of thermopower S with T−¹ for the $Cr_{1-x}Ni_xSb_2$ (x=0, 0.01).

Fig. 8. Variation of thermal conductivity $\kappa(i)$ and lattice thermal conductivity $\kappa_L(ii)$ with temperature T for $Cr_{1-x}Ni_xSb_2$ (x=0, 0.01, 0.05, and 0.10)

indicating that the major charge carriers are electrons in those compounds over the entire temperature range. A large peak is observed in the curve of S–T for CrSb₂ at ∼60 K (Fig. 7), which corresponds to the plateau in the ln ρ versus T curve, and is also related to the electronic change of the electron-spin system. It can be seen from Fig. 7 that |S| decreases with increasing Ni content in the whole temperature range due to an increase in the electron concentration caused by the substitution of Ni for Cr; while the disappearance of the peak in the curves of $S-T$ (Fig. 7) could originate from the suppression of the electronic change of the electron-spin system, which is in agreement with the elimination of the plateau in the curves of $\ln \rho - T$ ([Fig. 3\).](#page-1-0) In addition, the thermopower $|S|$ of CrSb₂ and Cr_{0.99}Ni_{0.01}Sb₂ could be expressed as the sum of a temperature independent term and a temperature dependent term [\[45\]:](#page-4-0)

$$
S = S_0 + \frac{k_B}{|e|} \frac{E_s}{k_B T}
$$
 (2)

where E_s is a characteristic energy for S, and S_0 is the thermopower in the high-temperature limit. The best fit of the experimental data to Eq. (2) yields two values of E_s : 35.7 meV and 15.9 meV for $CrSb₂$ and $Cr_{0.99}Ni_{0.01} Sb₂$, respectively. The characteristic energy E_s (=35.7 meV) for CrSb₂ is equal to the activation energy ΔE_2 $(=35.7 \text{ meV})$, suggesting that CrSb₂ is an intrinsic non-degenerate semiconductor. In the case of $Cr_{0.99}Ni_{0.01} Sb₂$, E_s (=15.9 meV) is smaller than ΔE_2 (=25.4 meV), indicating that the Fermi level E_F is higher than impurity level E_2 .

3.3. Thermal conductivity and figure of merit

Fig. 8(i) presents the total thermal conductivity (κ) as a function of temperature for $Cr_{1-x}Ni_xSb_2$. A maximum value of thermal conductivity for CrSb₂ and Cr_{0.99}Ni_{0.01}Sb₂ appears in the curve of κ –T. In contrast, the thermal conductivity of Cr_{0.95}Ni_{0.05}Sb₂ and $Cr_{0.9}Ni_{0.1}Sb₂$ shows weak temperature dependence in the temperature range from 50 to 310 K. The total thermal conductivity (κ) may be expressed as the sum of the lattice component $(\kappa_{\rm L})$ and the carrier component $(\kappa_{\mathcal{C}}): \kappa = \kappa_{\mathcal{L}} + \kappa_{\mathcal{C}}$. The $\kappa_{\mathcal{C}}$ values can be estimated from the Wiedemann–Franz's law as $\kappa_{\mathsf{C}} = L_0 T/\rho$, where L is the Lorentz number and ρ is the electrical resistivity. As a semiquantitative estimation, we use the value L_0 of free electrons for L (i.e. $L = L_0 = 2.44 \times 10^{-8} \text{ V}^2 \text{ K}^{-2}$) for all the samples. Consequently, the lattice thermal conductivity (κ_L) can be obtained from κ and $\kappa_{\rm C}$, as shown in Fig. 8(ii). By comparing Fig. 8(i) with (ii), it can be seen that the thermal conductivities of all compounds arise

Fig. 9. Variation of ZT with temperature T for $Cr_{1-x}Ni_xSb_2$ ($x = 0, 0.01, 0.05,$ and 0.10).

mainly from their lattice thermal conductivities. As compared to that of $CrSb₂$, the thermal conductivity of the doped compounds decreases from 30.3 W m⁻¹ K⁻¹ for x=0-5.1 W m⁻¹ K⁻¹ for x=0.1 at ∼50 K. This large and continuous decrease of low-temperature thermal conductivity could be ascribed to the enhancement of the phonon scattering by impurity (Ni) atoms. [Fig. 8\(i](#page-3-0)i) gives the lattice thermal conductivity (κ _L) as a function of T^a for Cr_{1−x}Ni_xSb₂ at low temperatures (T <30K). By the best fit of the experimental data one obtains $a = 1.9$ for $x = 0$, 1.5 for $x = 0.01$, 1.3 for $x = 0.05$, and 1.1 for $x = 0.1$, respectively. The power law of $\kappa_L \propto T^{1.9}$ for CrSb₂ suggests that both point-defects and grain-boundaries contribute to the scattering for temperatures down to 7 K. However, the dependence $\kappa_L \propto T^{1.1}$ for Cr_{0.9}Ni_{0.1}Sb₂ is a strong indication of the presence of electron–phonon interaction [46]. According to the usual phononic heat transport theory, the relationship between lattice thermal conductivity and temperatures above ∼30 K can be written as $\kappa_I \propto T^n$ ([Fig. 8\(ii](#page-3-0))), and the values of n are -1.04 and -1.02 for CrSb₂ and Cr_{0.99}Ni_{0.01}Sb₂, respectively. The results indicate that the values of *n* are basically equal to -1 within the experimental errors, suggesting that phonon–phonon interactions are the primary source of thermal resistance.

The figure of merit ZT values of $Cr_{1-x}Ni_xSb_2$ is calculated and presented as a function of temperature in Fig. 9. The ZT values for all the samples increase monotonically with increasing temperature. Above approximately ∼250 K, the ZT values of doped compounds are noticeably larger than those of $CrSb₂$. Specifically, the ZT value for Cr_0 99Ni_{0.01}Sb₂ is about 0.014 at 310 K, which is about 29% larger than that of $CrSb₂$, indicating that thermoelectric properties of CrSb₂ could be improved by proper substitution of Ni for Cr.

4. Conclusions

Substituted compounds $Cr_{1-x}Ni_xSb_2$ were synthesized, and the effect of Ni substitution on the transport and thermoelectric properties of $Cr_{1-x}Ni_xSb_2$ were investigated at the temperatures below 310 K. The results indicated that electrical resistivity (ρ) and thermopower (|S|) of $Cr_{1-x}Ni_xSb_2$ decreased greatly with increasing Ni content due to an increase in electron concentration caused by Ni substitution for Cr. In addition, experiments shown that low-temperature lattice thermal conductivity of $Cr_{1-x}Ni_xSb_2$ decreased substantially with increasing Ni content, presumably due to enhanced phonon scattering by doped Ni atoms. Moreover, the ZT value of $Cr_{0.99}Ni_{0.01}Sb_2$ is about 0.014 at 310 K, indicating that the thermoelectric properties of $CrSb₂$ could be improved by proper substitution of Ni for Cr. Furthermore, the Neel temperature of $Cr_{1-x}Ni_xSb_2$ decreased from 273 K for CrSb₂ to 195 K for $Cr_{0.9}Ni_{0.1}Sb₂$, which may be caused by the substitution of the low spin state Ni (3d⁶) for a high spin state Cr (3d²), weakening the effective moment of doping compounds.

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